

**Search Notes**

Application/Control No.

09/447,052

Examiner

Chau Nguyen

Applicant(s)/Patent under  
Reexamination

SUEHIRA, SEISHI

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	513	3/29/2006	CN
715	522	3/29/2006	CN
715	523	3/29/2006	CN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated Search on East Reports	3/29/2006	CN
NPL Search on IEEE Database	3/30/2006	CN